Notice of References Cited

Application/Control No. 09/916,064

Applicant(s)/Patent Under Reexamination SEIGLER ET AL.

Examiner

Art Unit 3729

Page 1 of 1

U.S. PATENT DOCUMENTS

Paul D Kim

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | Α | US-6,483,662 | 11-2002 | Thomas et al. | 360/126 |
| | В | US-6,455,177 | 09-2002 | Everitt et al. | 428/693 |
| | С | US-6,445,536 | 09-2002 | Rudy et al. | 360/126 |
| | D | US-5,841,692 | 11-1998 | Gallagher et al. | 365/173 |
| | Е | US-6,043,959 | 03-2000 | Crue et al. | 360/317 |
| | F | US- | | | |
| | G | US- | | | |
| | Н | US- | | | |
| | ı | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | , , , |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-----------------|----------------|
| | N | JP 09092906 A | 04-1997 | Japan | YAOI, TOSHIHIKO | H01L 43/08 |
| | 0 | JP 07326024 A | 12-1995 | Japan | SMITH, NEIL | G11B 05/39 |
| | Р | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | "Effect of microstructure on resistivity and GMR ratio in ion beam deposited spin valves"; Bailey, W.E.; Guarisco, D.; Wang, S.X.; Magnetics, IEEE Transactions on , Volume: 34 Issue: 4; July 1998; Page(s): 957 -959. |
| | ٧ | "Giant magnetoresistance of current-perpendicular exchange-biased spin-valves of Co/Cu"; Reilly, A.C.; Chiang, WC.; Park, W.; Hsu, S.Y.; Loloee, R.; Magnetics, IEEE Transactions on , Volume: 34 Issue: 4 , July 1998; Page(s): 939 -941. |
| | w | |
| | х | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.